MICROCONTROLLER DIVISION

QUALITY & RELIABILITY

Traceability

TRACEABILITY PROCEDURE

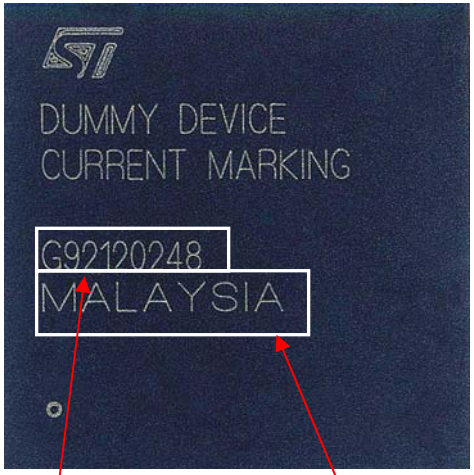
- The concept of the traceability is based on the top side marking of each single device of a "traceability code“.
- A computerized system called "trace", is able starting from the traceability code to trace back history of the lot from the diffusion up to the shipments.
- The traceability code definition was changed end of 2003 from “WATNNYYWW” TO “PPYWWLLL”.

WATNNYYWW	
W	DIFFUSION PLANT CODE
A	ASSEMBLY PLANT CODE
T	TESTING PLANT CODE
NN	TEST LOT SEQUENTIAL NUMBER
YYWW	DATE CODE

PPYWWLLL	
PP	ASSEMBLY PLANT CODE
Y	LAST DIGIT OF THE YEAR
WW	WEEK
LLL	TEST LOT SEQUENTIAL NUMBER

Enhanced Traceability Code Examples

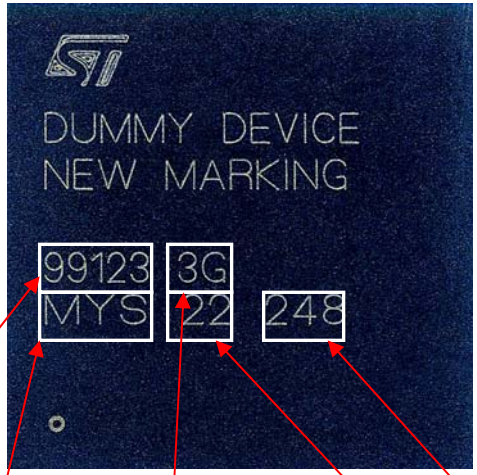
Previous Trace code



WATNNYYWW

Country of Origin (Assembly)

Enhanced Trace code



PPLLL

Country of Origin (Assembly)
As defined in ISO 3166-1 Specification

WX is the Wafer Fab Production Area Code

TF is the Test and Finishing Production Area Code

Date Code YWW

MCD COMMONLY USED SITES AND CODES

DIFFUSION	
ABOV	FL
AGRATE AG8	V1
AGRATE R2	VA
AMK 6	V6
CATANIA M5 8”	V5
CROLLES	VJ
CHARTERED F2	F2
PHOENIX	VP
ROUSSET 8”	VG
TOWER	85
WF3	93
WF8	98

ASSEMBLY	
AMKOR ATK (KOREA)	HP
AMKOR ATP (PHILIPPINES)	7B
ASE TAIWAN	AA
CARSEM M/S MALAYSIA	9Y
MALTA	22
MUAR	99
SHENZHEN	GK
SIGNETICS S2	HT
SIGNETICS S3	HS
STATS CHIPPAC SINGAPORE	8N
STATS CHIPPAC KOREA	HH
STATS CHIPPAC MALAYSIA	9H

TEST	
AGRATE	11
AMKOR ATP	7B
TOA PAYOH	88
PHOENIX	DE
MALTA	22
MUAR	99
ROUSSET	3R
GRENOBLE	3A
KYEC	AK